7/19/2012

RELIABILITY MONITOR REPORT
FOR

San Antonio Silicon Gate 0.5µm CMOS (E35)

MAXIM Integrated Products

120 San Gabriel Dr.
Sunnyvale, CA 94086

This Report was prepared by
Maxim Reliability Engineering

Summary:

The data in the tables that follow was generated as the result of an on-going Process Reliability Monitor. The specific products in this process monitor are:

DS2704R	DS3232M

The calculated failure rate for devices using this process is:

FAILURE RATE: MTTF (YRS): 11656 QUANTITY: 160 FAILS: 0 FITS: 9.8

The parameters used to calculate this failure rate are as follows:

Cf: 60% Ea: 0.7 Tu: 25 °C

The reliability data follows and in this section is the detailed reliability data by stress. The reliability data section includes the latest data available. This report covers data between 7/1/2011 and 6/30/2012 .

Process Information:

Process Description: San Antonio Silicon Gate 0.5µm CMOS (E35)

OPERATING LIFE

DESCRIPTION	DATE CODE	TEST VEHICLE	CONDITION	READPOINT		QUANTITY	FAILS	LOT NO.
HIGH TEMP OP LIFE	1135	DS2704R	125C, 5.5 VOLTS	1000	HRS	80	0	FJ268977ADA-IME
HIGH TEMP OP LIFE	1150	DS3232M	125C, 4.7 VOLTS (PSA)	240	HRS	80	0	ZX272110AA-NPI
					Total:		**0**	

STORAGE LIFE

DESCRIPTION	DATE CODE	TEST VEHICLE	CONDITION	READPOINT		QUANTITY	FAILS	LOT NO.
STORAGE LIFE	1135	DS2704R	150C	1000	HRS	80	0	FJ268977ADA-IME
					Total:		**0**	

TEMPERATURE CYCLE

DESCRIPTION	DATE CODE	TEST VEHICLE	CONDITION	READPOINT		QUANTITY	FAILS	LOT NO.
TEMP CYCLE, 5' RAMP, 10' DWELL	1135	DS2704R	-55C TO 125C	1000	CYS	80	0	FJ268977ADA-IME
					Total:		**0**	

UNBIASED MOISTURE RESISTANCE

DESCRIPTION	DATE CODE	TEST VEHICLE	CONDITION	READPOINT		QUANTITY	FAILS	LOT NO.
HAST, NO BIAS	1135	DS2704R	130C, 85% R.H.	96	HRS	80	0	FJ268977ADA-IME
					Total:		**0**	

FAILURE RATE: MTTF (YRS): 11656 QUANTITY: 160 FAILS: 0 FITS: 9.8